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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/665,253	EPSTEIN	
Examiner	Art Unit	
Hien N. Nauven	2824	

SEARCHED			
Class	Subclass	Date	Examiner
365	158	5/2/2005	HN
	171		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEAR(INCLUDING SE	CH NOT	ES STRATEGY)
		DATE	EXMR
EAST		5/2/2005	HN